

Notice of References Cited		Application/Control No. 10/559,391	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner MICHAEL M. BERNSHTEYN	Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,448,354	09-2002	Hieda et al.	526/319
*	B	US-5,153,283	10-1992	Fujita et al.	526/144
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000313704 A	11-2000	Japan	TAKIZAWA et al.	
	O	JP 11228645 A	08-1999	Japan	TAKEMOTO et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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